

	A	B	C	D	E	F	H	I
1	Product	Description	Resolution	Status	Type	Release Fixed	Priority	Due Date
2	Mk4	ESD Spiral test allow non-VI parametric pin groups for ESD tes. Same as ESD Zap only.	H8 on IST's list.	In Progress	Bug		High	
3	Mk4	Import - Continuity Test Import always adds a PSU operation called "PowerContinuity"		In Progress	Bug		High	
4	Mk4	Import (Latchup) – the stress method is always set to "Incremental", even when a different method is set in the import file. The user must edit every latchup test in a testplan to change it		In Progress	Bug		High	
5	Mk4	Manual latchup - MW exception message states that "Pin 6 not mapped". File <b>LSOON 1 Gate 7 Supply</b> under Regression Tests		In Progress	Bug		High	
6	Mk4	If an IDD test is run on alphanumeric device and then a curve trace on a numeric one, an exception is thrown stating that a pin is not found on the DUT's pin list	AAT: Looks similar to Manual Latchup bug on <b>LSOON 1 Gate 7 device</b> . This is MW bug - pin lists are not disposed of properly. Rebooting the TesterDaemon will clear the problem.	In Progress	Bug		High	
7	Mk4	Some device files created by importing legacy Mk2/Paragon files may not open if they have a manual test in them and are interfacing with lower PSU count machines.		In Progress	Bug		High	
8	Mk4	Curve Compare False Failures - the tester will report curve compare failures even though it has clearly passed. When run on the PC the compare is done correctly	01/07/07. Nathan has implemented data collection routine which will help with the investigation. 02/05/08. Collected data received from the field 03/10/08. More data required, data collection is modified and sent to customer	Under Investigation	Bug		High	
9	Mk4	The Controller App may hang when multiple PMs connected and the test is running that generates a lot of result data	Reported by MEFAS. Unable to reproduce in the lab - need further investigation	Can't Reproduce	Bug		Low	
10	Mk4	Clone Device, Delete Pingroup, tree structure not refreshed		Can't Reproduce	Bug		Low	
11	Mk4	Latchup I results - Park values are missing from results for INPUT groups that were stressed		Non-repeatable	Bug		Low	
12	Mk4	Preconditioning vectors are incorrect for the 1.2KHz vector clock speed. This frequency causes the stress pulse to disappear and the parking level to be ignored. It occurs only with this frequency and it occurs regardless of whether or not the stress pin is actually being vectored.	The problem will be fixed in future releases. For now, avoid using the 1.2KHz vector clock frequency	Submitted	Bug		Low	
13	Mk4	During calibration, if the matrix selftest is run, then the VI calibration and then the matrix selftest again, FW reports a failure connecting to VI-0. [ERROR]:1192461394:1:1:vinit.c:533:vi_open_a dd:Cannot open V/I board 0 - not connected to matrix	FW error	Submitted	Bug		Low	
14	Mk4	Manual Curve Trace - Power pin to Power, Ground to Curve Trace Ground, Input of Curve Trace. System does not allow running.	TM was able to reproduce but unable to repeat it again. Will investigate further.	Non-repeatable	Bug		Medium	
15	Mk4	Running a single-column vector during a test causes the MW to throw up an exception stating that at least 2 vector states required to run the vector	Is it intentional? Why?	Under Investigation	Not A Bug		Medium	
16	Mk4	Latchup Testplan, Skip Failed Pins mode – an IDD test failure causes all subsequent latchup tests to be skipped		Under Investigation	Bug		Medium	
17	Mk4	Check box Include Curves is always disabled in the Print results Wizard		Fixed	Bug		Low	
18	Mk4	Some device files created by cloning may not run correctly if they have a latchup tests in them.	Workaround: Saving and closing the file and then re-opening it again will fix the problem	In Progress	Bug		Low	